- 13. An X-ray inspection apparatus according to Claim 6, wherein the straight line to be the central axis and the axis of rotation is set to be vertical to a stage on which the sample is placed.
- 14. An X-ray inspection apparatus according to Claim 6, comprising a sliding mechanism whereby the X-ray detecting means is slided in a direction vertical to the X-ray incidence plane.
- 15. An X-ray inspection apparatus according to Claim 7, comprising a sliding mechanism whereby the X-ray detecting means is slided in a direction vertical to the X-ray incidence plane.
- 16. An X-ray inspection apparatus according to Claim 8, comprising a sliding mechanism whereby the X-ray detecting means is slided in a direction vertical to the X-ray incidence plane.
- 17. An X-ray inspection apparatus according to claim 6, comprising a stage transfer means for two-dimensionally transferring a stage on which the sample is placed.
- 18. An X-ray inspection apparatus according to Claim 7, comprising a stage transfer means for two-dimensionally transferring a stage on which the sample is placed.
- 19. An X-ray inspection apparatus according to Claim 8, comprising a stage transfer means for two-dimensionally transferring a stage on which the sample is placed.
- 20. An X-ray inspection apparatus according to Claim 9, comprising a stage transfer means for two-dimensionally transferring a stage on which the sample is placed.--